

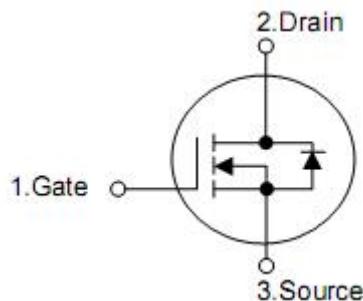
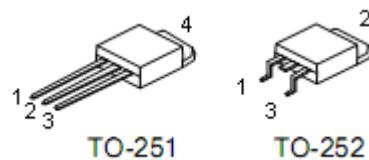
## 1. Features

- $R_{DS(on)}=77\text{m}\Omega$  @  $V_{GS}=10\text{V}$
- Super low gate charge
- Green device available
- Excellent CdV/dt effect decline
- Advanced high cell density trench technology

## 2. Description

The KNX7115A is the highest performance trenched N-ch MOSFETs with extreme high cell density, which provide excellent RDSON and gate charge for most of the synchronous buck converter applications. The KNX7115A meet the RoHs and Green Product requirement, 100% EAS guaranteed with full function reliability approved.

## 3. Pin configuration



Pin	Function
1	Gate
2	Drain
3	Source

## 4. Ordering Information

Part Number	Package	Brand
KND7115A	TO-252	KIA
KNU7115A	TO-251	KIA

## 5. Absolute maximum ratings

( $T_A=25^\circ\text{C}$ ,unless otherwise noted)

Parameter	Symbol	Rating	Units
Drain-source voltage	$V_{DSS}$	150	V
Gate-source voltage	$V_{GS}$	$\pm 20$	V
Continuous drain current $V_{GS} @ 10V^1$	$I_D$	20	A
		14	
		3	
		2.5	
Pulsed drain current <sup>2</sup>	$I_{DM}$	40	A
Single pulse avalanche energy <sup>3</sup>	EAS	53	mJ
Avalanche current	$I_{AS}$	18	A
Total power dissipation <sup>3</sup>	$P_D$	72.6	W
		2.1	W
Junction and storage temperature range	$T_J, T_{STG}$	-55 to 150	°C

## 6. Thermal characteristics

Parameter	Symbol	Typ	Max	Unit
Thermal resistance junction-case <sup>1</sup>	$R_{thJC}$	-	1.72	°C/W
Thermal resistance junction-ambient <sup>1</sup>	$R_{thJA}$	-	60	

## 7.Electrical characteristics

( $T_J=25^\circ\text{C}$ ,unless otherwise noted)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Units
Drain-Source breakdown voltage	$\text{BV}_{\text{DSS}}$	$\text{V}_{\text{GS}}=0\text{V}, \text{I}_D=-250\mu\text{A}$	150	-	-	V
Drain-Source Leakage Current	$\text{I}_{\text{DSS}}$	$\text{V}_{\text{DS}}=120\text{V}, \text{V}_{\text{GS}}=0\text{V}, \text{T}_J=25^\circ\text{C}$	-	-	1	$\mu\text{A}$
		$\text{V}_{\text{DS}}=120\text{V}, \text{V}_{\text{GS}}=0\text{V}, \text{T}_J=55^\circ\text{C}$	-	-	5	
Gate-source leakage current	$\text{I}_{\text{GSS}}$	$\text{V}_{\text{GS}}=\pm 20\text{V}, \text{V}_{\text{DS}}=0\text{V}$	-	-	$\pm 100$	nA
Gate threshold voltage	$\text{V}_{\text{GS(th)}}$	$\text{V}_{\text{DS}}=\text{V}_{\text{GS}}, \text{I}_D=250\mu\text{A}$	1.2	-	2.5	V
Static drain-source on- resistance <sup>2</sup>	$\text{R}_{\text{DS(on)}}$	$\text{V}_{\text{GS}}=10\text{V}, \text{I}_D=10\text{A}$	-	77	88	$\text{m}\Omega$
		$\text{V}_{\text{GS}}=4.5\text{V}, \text{I}_D=10\text{A}$	-	82	100	
Forward transconductance	$\text{g}_{\text{FS}}$	$\text{V}_{\text{DS}}=5\text{V}, \text{I}_D=10\text{A}$	-	33	-	S
Total gate charge(10V)	$\text{Q}_g$	$\text{V}_{\text{DS}}=75\text{V}, \text{V}_{\text{GS}}=4.5\text{V}$ $\text{I}_D = 10\text{A}$	-	25.1	-	nC
Gate-source charge	$\text{Q}_{\text{gs}}$		-	6.8	-	
Gate-drain charge	$\text{Q}_{\text{gd}}$		-	12.6	-	
Turn-on delay time	$\text{t}_{\text{d(on)}}$	$\text{V}_{\text{DD}}=75\text{V}, \text{R}_G=3.3\Omega, \text{V}_{\text{GS}}=10\text{V}$ $\text{I}_D=10\text{A}$	-	13	-	ns
Rise time	$\text{t}_r$		-	8.2	-	
Turn-off delay time	$\text{t}_{\text{d(off)}}$		-	25	-	
Fall time	$\text{t}_f$		-	11	-	
Input capacitance	$\text{C}_{\text{iss}}$	$\text{V}_{\text{GS}}=0\text{V}, \text{V}_{\text{DS}}=25\text{V}$ $\text{F}=1.0\text{MHz}$	-	2285	-	pF
Output capacitance	$\text{C}_{\text{oss}}$		-	110	-	
Reverse transfer capacitance	$\text{C}_{\text{rss}}$		-	83	-	
Diode characteristics						
Continuous source current <sup>1.5</sup>	$\text{I}_s$	$\text{V}_G=\text{V}_D=0\text{V}, \text{Force}$ current	-	-	20	A
Pulsed source current <sup>2.5</sup>	$\text{I}_{\text{SM}}$		-	-	40	A
Diode forward voltage <sup>2</sup>	$\text{V}_{\text{SD}}$	$\text{V}_{\text{GS}}=0\text{V}, \text{I}_s=-1\text{A}, \text{T}_J=25^\circ\text{C}$	-	-	1.2	V
Reverse recovery time	$\text{t}_{\text{rr}}$	$\text{I}_F=10\text{A}, \text{dI}/\text{dt}=100\text{A}/\text{us}, \text{T}_J=25^\circ\text{C}$	-	37	-	nS
Reverse recovery charge	$\text{Q}_{\text{rr}}$		-	263	-	nC

Note:1. The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.

2. The data tested by pulsed, pulse width  $\leq 300\text{us}$ ,duty cycle  $\leq 2\%$ .
3. The EAS data shows Max.rating. The test condition is  $\text{V}_{\text{DD}}=25\text{V}, \text{V}_{\text{GS}}=10\text{V}, \text{L}=0.3\text{mH}, \text{I}_{\text{AS}}=18\text{A}$ .
4. The power dissipation is limited by  $150^\circ\text{C}$  junction temperature.
5. The data is theoretically the same as  $\text{I}_D$  and  $\text{I}_{\text{DM}}$ , in real applications, should be limited by total power dissipation.

## 6. Test circuits

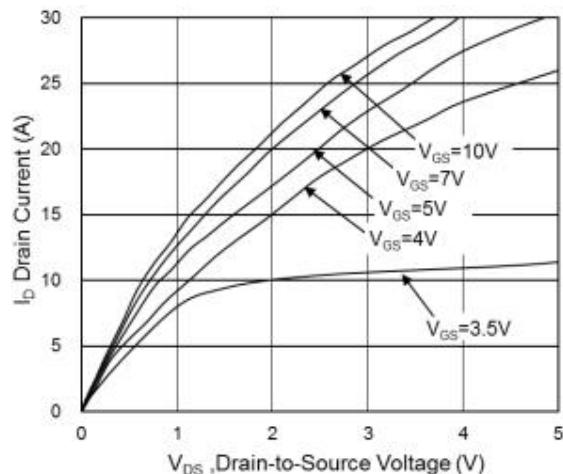


Fig.1 Typical Output Characteristics

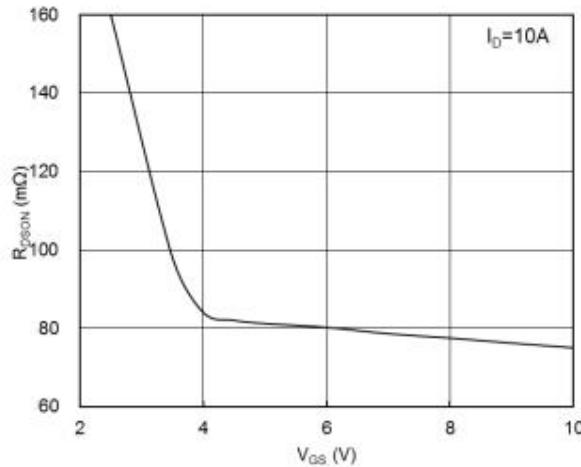


Fig.2 On-Resistance vs. Gate-Source Voltage

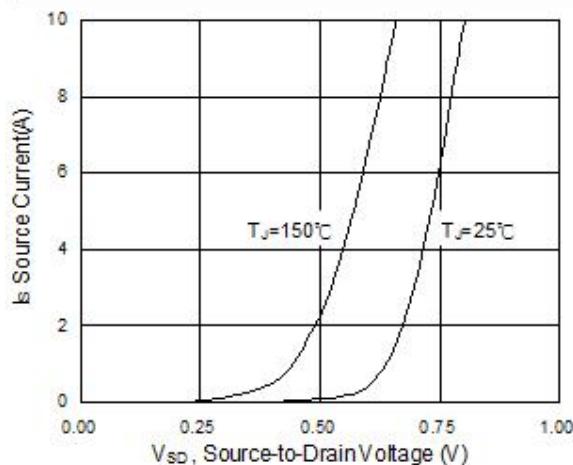


Fig.3 Forward Characteristics of Reverse

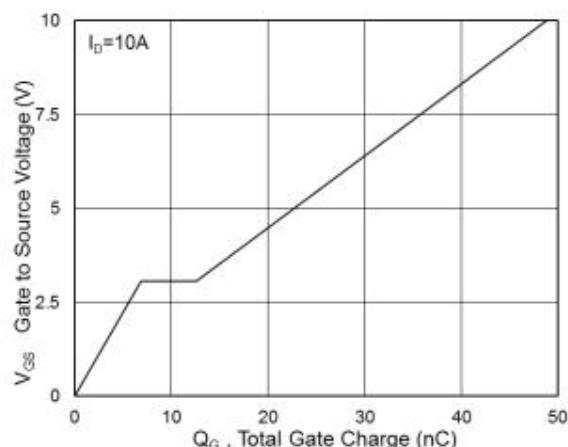


Fig.4 Gate-Charge Characteristics

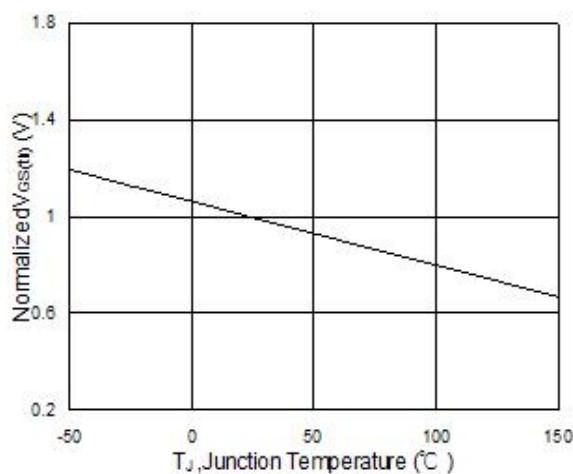


Fig.5 Normalized  $V_{GS(th)}$  vs.  $T_J$

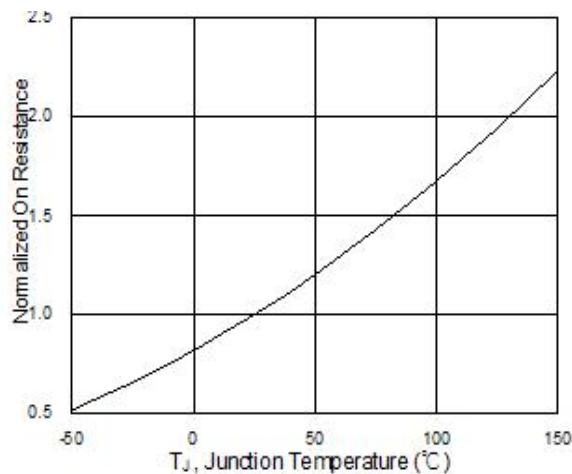


Fig.6 Normalized  $R_{DS(on)}$  vs.  $T_J$

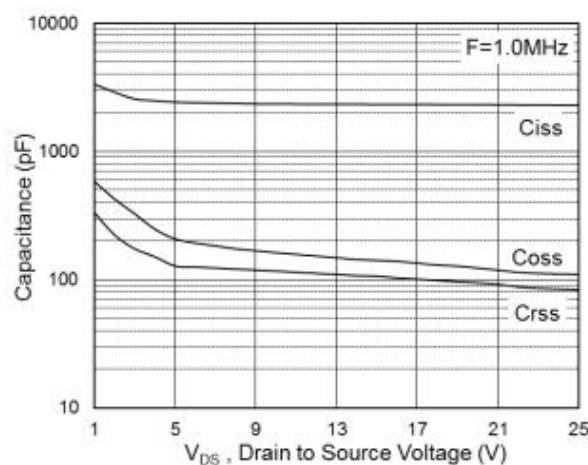
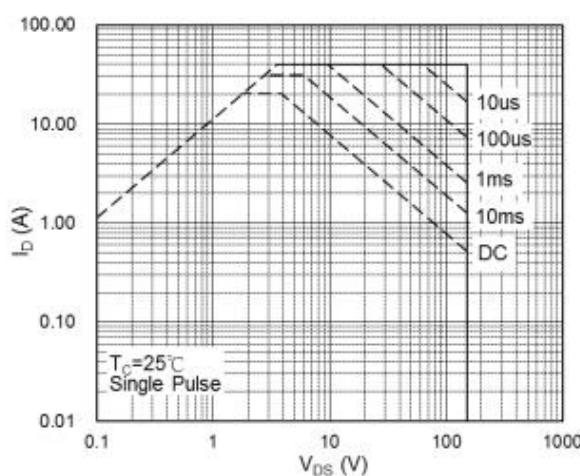


Fig.7 Capacitance

Fig.8 Safe Operating Area

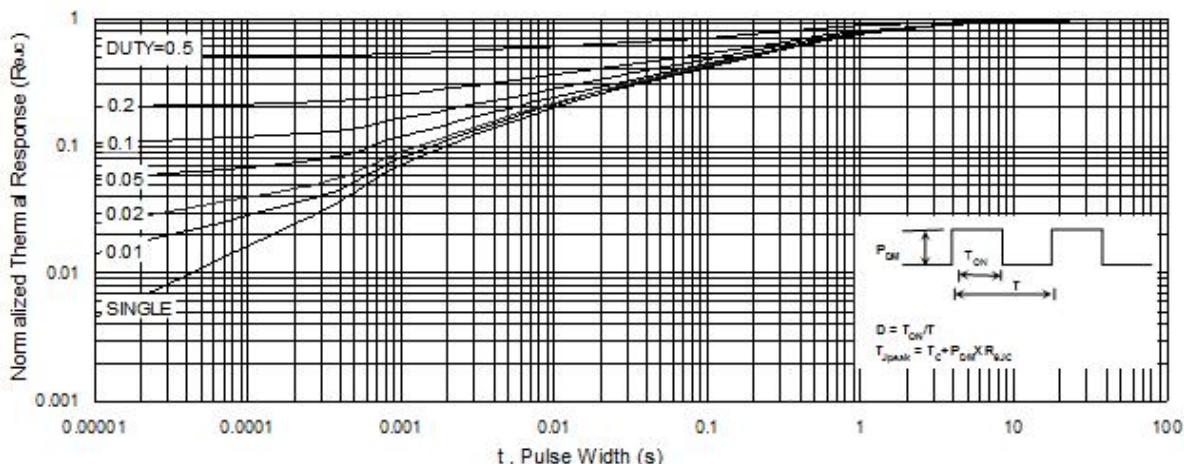


Fig.9 Normalized Maximum Transient Thermal Impedance

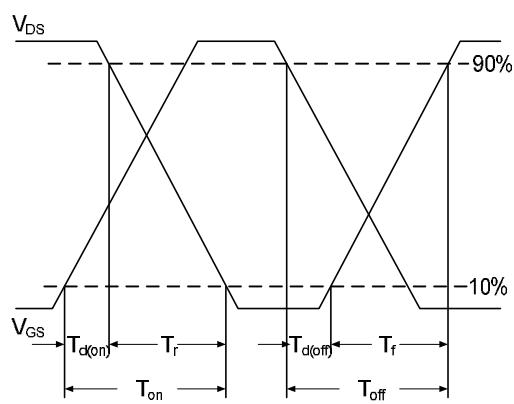


Fig.10 Switching Time Waveform

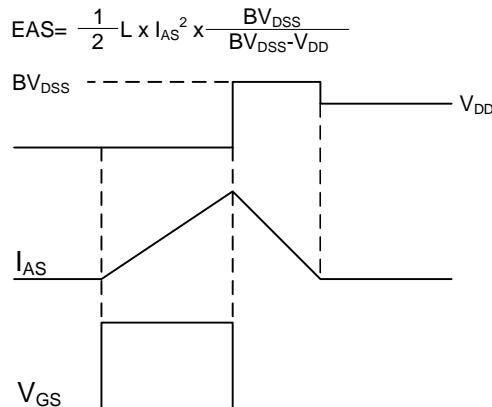


Fig.11 Unclamped Inductive Switching Waveform